SDAS039F - DECEMBER 1983 - REVISED JANUARY 1995

- Independent Registers for A and B Buses
- Multiplexed Real-Time and Stored Data
- Choice of True or Inverting Data Paths
- Choice of 3-State or Open-Collector Outputs
- Package Options Include Plastic Small-Outline (DW) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (NT) and Ceramic (JT) 300-mil DIPs

DEVICE	OUTPUT	LOGIC
SN54ALS646, SN74ALS646A, 'AS646	3 state	True
SN54ALS648, SN74ALS648A, SN74AS648	3 state	Inverting

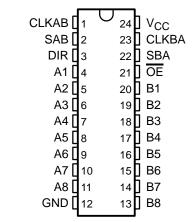
description

These devices consist of bus-transceiver circuits with 3-state or open-collector outputs, D-type flip-flops, and control circuitry arranged for multiplexed transmission of data directly from the data bus or from the internal storage registers. Data on the A or B bus is clocked into the registers on the low-to-high transition of the appropriate clock (CLKAB or CLKBA) input. Figure 1 illustrates the four fundamental bus-management functions that can be performed with the octal bus transceivers and registers.

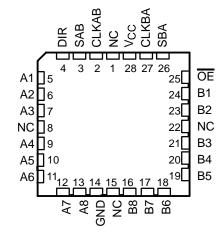
Output-enable (OE) and direction-control (DIR) inputs control the transceiver functions. In the transceiver mode, data present at the high-impedance port may be stored in either or both registers.

The select-control (SAB and SBA) inputs can multiplex stored and real-time (transparent mode)

SN54ALS646, SN54ALS648, SN54AS646 . . . JT PACKAGE SN74ALS646A, SN74ALS648A, SN74AS646, SN74AS648 . . . DW OR NT PACKAGE (TOP VIEW)



SN54ALS646, SN54ALS648, SN54AS646 . . . FK PACKAGE (TOP VIEW)



NC - No internal connection

data. The circuitry used for select control eliminates the typical decoding glitch that occurs in a multiplexer during the transition between stored and real-time data. DIR determines which bus receives data when \overline{OE} is low. In the isolation mode (\overline{OE} high), A data may be stored in one register and/or B data may be stored in the other register.

When an output function is disabled, the input function is still enabled and can be used to store and transmit data. Only one of the two buses, A or B, may be driven at a time.

The -1 version of the SN74ALS646A is identical to the standard version, except that the recommended maximum I_{OL} in the -1 version is increased to 48 mA. There are no -1 versions of the SN54ALS646, SN54ALS648, or SN74ALS648A.

The SN54ALS646, SN54ALS648, and SN54AS646 are characterized for operation over the full military temperature range of –55°C to 125°C. The SN74ALS646A, SN74ALS648A, SN74AS646, and SN74AS648 are characterized for operation from 0°C to 70°C.



SDAS039F - DECEMBER 1983 - REVISED JANUARY 1995

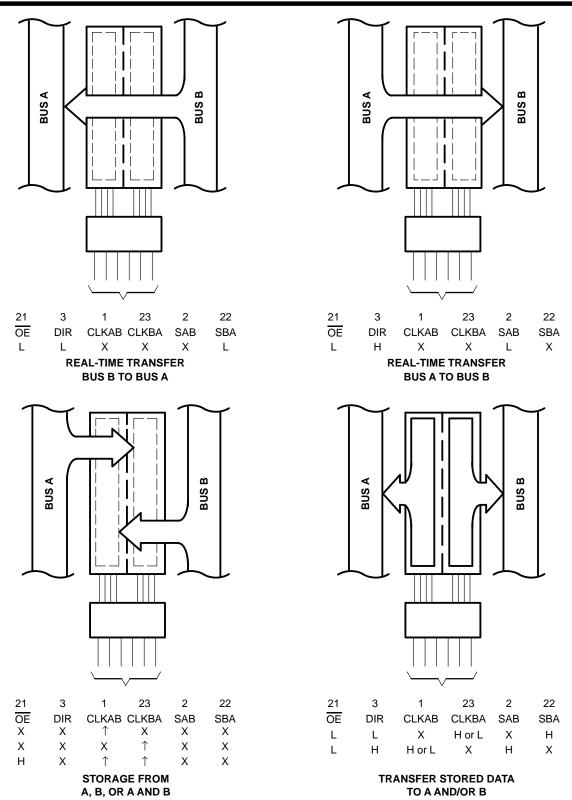


Figure 1. Bus-Management Functions

Pin numbers shown are for the DW, JT, and NT packages.



SDAS039F - DECEMBER 1983 - REVISED JANUARY 1995

Function Tables

SN54ALS646, SN54AS646, SN74ALS646A, SN74AS646

		INP	UTS			DAT	A I/O	OPERATION OR FUNCTION
ŌĒ	DIR	CLKAB	CLKBA	SAB	SBA	A1-A8	B1-B8	OPERATION OR FUNCTION
Х	Х	1	Х	Х	Х	Input	Unspecified [†]	Store A, B unspecified [†]
Х	Х	Х	\uparrow	X	Χ	Unspecified [†]	Input	Store B, A unspecified [†]
Н	Х	1	↑	Х	Х	Input	Input	Store A and B data
Н	Χ	H or L	H or L	Χ	Χ	Input disabled	Input disabled	Isolation, hold storage
L	L	Х	Х	Х	L	Output	Input	Real-time B data to A bus
L	L	Χ	H or L	X	Н	Output	Input	Stored B data to A bus
L	Н	Х	Х	L	Х	Input	Output	Real-time A data to B bus
L	Н	H or L	Χ	Н	Χ	Input	Output	Stored A data to B bus

[†] The data output functions can be enabled or disabled by various signals at $\overline{\text{OE}}$ and DIR. Data input functions are always enabled; i.e., data at the bus terminals is stored on every low-to-high transition of the clock inputs.

SN54ALS648, SN74ALS648A, SN74AS648

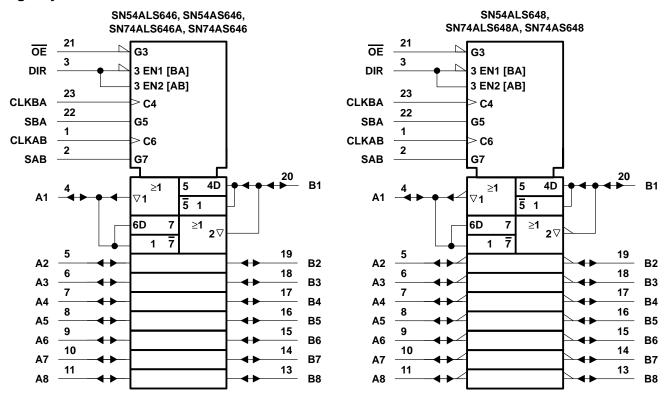
		INP	UTS			DAT	A I/O	OPERATION OR FUNCTION
OE	DIR	CLKAB	CLKBA	SAB	SBA	A1-A8	B1-B8	OPERATION OR FUNCTION
Х	Х	1	Х	Х	Х	Input	Unspecified [†]	Store A, B unspecified [†]
Х	X	Χ	1	X	Χ	Unspecified [†]	Input	Store B, A unspecified [†]
Н	Х	1	1	Х	Х	Input	Input	Store A and B data
Н	X	H or L	H or L	Χ	Χ	Input disabled	Input disabled	Isolation, hold storage
L	L	Х	Х	Х	L	Output	Input	Real-time B data to A bus
L	L	Χ	H or L	X	Н	Output	Input	Stored \overline{B} data to A bus
L	Н	Х	Х	L	Х	Input	Output	Real-time \overline{A} data to B bus
L	Н	H or L	Χ	Н	Χ	Input	Output	Stored \overline{A} data to B bus

[†] The data output functions can be enabled or disabled by various signals at OE and DIR. Data input functions are always enabled; i.e., data at the bus terminals is stored on every low-to-high transition of the clock inputs.



SDAS039F - DECEMBER 1983 - REVISED JANUARY 1995

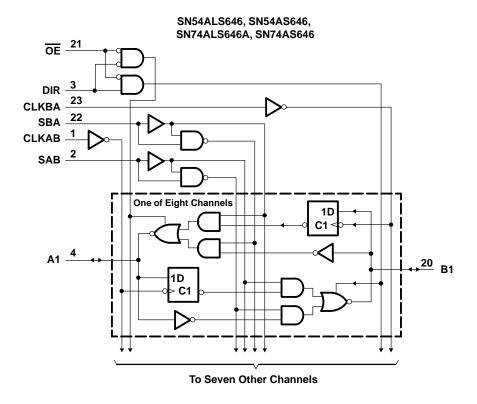
logic symbols†

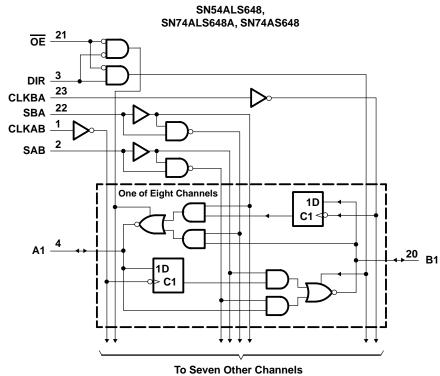


[†]These symbols are in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. Pin numbers shown are for the DW, JT, and NT packages.



logic diagrams (positive logic)





Pin numbers shown are for the DW, JT, and NT packages.



SDAS039F - DECEMBER 1983 - REVISED JANUARY 1995

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, V _{CC}			. 7 V
Input voltage, V _I : Control inputs			. 7 V
I/O ports			5.5 V
Operating free-air temperature range, TA:	SN54ALS646	−55°C to	125°C
	SN74ALS646A	0°C to	o 70°C
Storage temperature range		−65°C to	150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions

		SN	54ALS6	46	SN7	'4ALS64	6A	LINIT
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Vсс	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
V_{IH}	High-level input voltage	2			2			V
V_{IL}	Low-level input voltage			0.7			0.8	V
ЮН	High-level output current			-12			-15	mA
l	Lavadaval autori avenuet			12			24	
lOL	Low-level output current						48‡	mA
fclock	Clock frequency	0		35	0		40	MHz
t _W	Pulse duration, CLKBA or CLKAB high or low	14.5			12.5			ns
t _{su}	Setup time, A before CLKAB↑ or B before CLKBA↑	15			10			ns
t _h	Hold time, A after CLKAB↑ or B after CLKBA↑	0			0			ns
TA	Operating free-air temperature	-55		125	0		70	°C

 $[\]ddagger$ Applies only to the -1 version and only if VCC is maintained between 4.75 V and 5.25



SDAS039F - DECEMBER 1983 - REVISED JANUARY 1995

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

		TEST COL	IDITIONS	SN	54ALS6	46	SN7	4ALS64	6A	UNIT	
	PARAMETER	TEST CON	NDITIONS	MIN	TYP [†]	MAX	MIN	TYP [†]	MAX	UNII	
VIK		$V_{CC} = 4.5 \text{ V},$	I _I = -18 mA			-1.2			-1.2	V	
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V},$	$I_{OH} = -0.4 \text{ mA}$	V _{CC} -2			V _{CC} -2				
\/a			$I_{OH} = -3 \text{ mA}$	2.4	3.2		2.4	3.2		V	
VOH		l -	$I_{OH} = -12 \text{ mA}$	2						v	
			$I_{OH} = -15 \text{ mA}$				2				
			I _{OL} = 12 mA		0.25	0.4		0.25	0.4		
VOL		V _{CC} = 4.5 V	I _{OL} = 24 mA					0.35	0.5	V	
			$I_{OL} = 48 \text{ mA}^{\ddagger}$					0.35	0.5		
١.	Control inputs	V00 = 55 V	V _I = 7 V			0.1			0.1	mA	
lį	A or B ports	V _{CC} = 5.5 V	V _I = 5.5 V			0.1			0.1	ША	
	Control inputs	\/ F F \/	\\. \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\			20			20		
ΊΗ	A or B ports§	V _{CC} = 5.5 V,	V _I = 2.7' V			20			20	μΑ	
	Control inputs	V 55V	V			-0.2			-0.2	4	
IIL	A or B ports§	V _{CC} = 5.5 V,	V _I =70:4′ V			-0.2			-0.2	mA	
Io¶		V _{CC} = 5.5 V,	V _O = 2.25 V	-20		-112	-30		-112	mA	
			Outputs high		47	76		47	76	mA	
Icc		V _{CC} = 5.5 V	Outputs low		55	88		55	88		
			Outputs disabled		55	88		55	88		

[†] All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

 $[\]ddagger$ Applies only to the -1 version and only if VCC is maintained between 4.75 V and 5.25 \$ For I/O ports, the parameters I_{IH} and I_{IL} include the off-state output current.

¹ The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, IOS.

SDAS039F - DECEMBER 1983 - REVISED JANUARY 1995

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _C C _L R1 R2 T _A	UNIT			
			SN54A	LS646	SN74AL	S646A	
			MIN	MAX	MIN	MAX	
f _{max}			35		40		MHz
^t PLH	CLKBA or CLKAB	A or B	10	35	7	30	ns
^t PHL	CENDA OF CENAD	AOID	5	20	5	17	113
^t PLH	A or B	B or A	5	22	3	20	ns
^t PHL	7010	DOIA	3	15	3	12	113
^t PLH	SBA or SAB‡	A or B	10	40	7	35	ns
^t PHL	(stored data low)	7015	5	23	5	20	113
^t PLH	SBA or SAB‡	A or B	8	30	6	25	ns
^t PHL	(stored data high)	AOID	5	24	5	20	115
^t PZH	ŌĒ	A or B	3	20	2	17	ns
^t PZL	OE	AOID	5	22	4	20	115
^t PHZ	ŌĒ	A or B	1	12	1	10	ns
^t PLZ	OE	7010	1	20	2	16	110
^t PZH	DIR	A or B	5	38	3	30	ns
^t PZL	DIIX	7010	5	30	4	25	110
^t PHZ	DIR	A or B	1	12	1	10	ns
^t PLZ	DIK	7010	2	21	2	16	110

[†] For conditions shown MIN or MAX, use the appropriate value specified under recommended operating conditions.

[‡] These parameters are measured with the internal output state of the storage register opposite that of the bus input.

SDAS039F - DECEMBER 1983 - REVISED JANUARY 1995

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, V _{CC}			. 7 V
Input voltage, V _I : Control inputs			. 7 V
I/O ports			5.5 V
Operating free-air temperature range, TA:	SN54ALS648	−55°C to	125°C
	SN74ALS648A	0°C to	70°C כ
Storage temperature range		-65°C to	150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions

		SN	I54ALS6	48	SN7	'4ALS64	8A	UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	UNII
VCC	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
V_{IH}	High-level input voltage	2			2			V
V_{IL}	Low-level input voltage			0.7			0.8	V
IOH	High-level output current			-12			-15	mA
lOL	Low-level output current			12			24	mA
fclock	Clock frequency	0		35	0		40	MHz
t _W	Pulse duration, CLKBA or CLKAB high or low	14.5			12.5			ns
t _{su}	Setup time, A before CLKAB↑ or B before CLKBA↑	15			10			ns
t _h	Hold time, A after CLKAB↑ or B after CLKBA↑	0		·	0			ns
TA	Operating free-air temperature	-55		125	0		70	°C



SDAS039F - DECEMBER 1983 - REVISED JANUARY 1995

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	DADAMETED	TEST 00	NDITIONS	SN	54ALS6	48	SN7	4ALS64	8A	UNIT	
	PARAMETER	lesi co	NDITIONS	MIN	TYP [†]	MAX	MIN	TYP [†]	MAX	UNII	
VIK		V _{CC} = 4.5 V,	I _I = -18 mA			-1.2			-1.2	V	
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V},$	$I_{OH} = -0.4 \text{ mA}$	V _{CC} -2			V _{CC} -2				
\/~			$I_{OH} = -3 \text{ mA}$	2.4	3.2		2.4	3.2		V	
VOH		V _{CC} = 4.5 V	$I_{OH} = -12 \text{ mA}$	2						V	
			$I_{OH} = -15 \text{ mA}$				2				
V/01		V _{CC} = 4.5 V	I _{OL} = 12 mA		0.25	0.4		0.25	0.4	V	
VOL		VCC = 4.5 V	I _{OL} = 24 mA					0.35	0.5		
١.	Control inputs	V _{CC} = 5.5 V	V _I = 7 V			0.1			0.1	mA	
Ħ	A or B ports		V _I = 5.5 V			0.1			0.1		
	Control inputs	V 55V	\			20			20	^	
ΊΗ	A or B ports‡	V _{CC} = 5.5 V,	V _I = 2.7' V			20			20	μΑ	
Γ.	Control inputs	V 55V	\/ \(COLW() \/ \)			-0.2			-0.2	4	
¹l∟	A or B ports‡	V _{CC} = 5.5 V,	V _I = 0.4′ V			-0.2			-0.2	mA	
IO§		V _{CC} = 5.5 V,	V _O = 2.25 V	-20		-112	-30		-112	mA	
			Outputs high		47	76		47	76		
Icc			V _{CC} = 5.5 V	Outputs low		57	88		57	88	mA
			Outputs disabled		57	88		57	88		

[†] All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

[‡] For I/O ports, the parameters I_{IH} and I_{IL} include the off-state output current.

[§] The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, IOS.

SDAS039F - DECEMBER 1983 - REVISED JANUARY 1995

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 4.5 C _L = 50 pF R1 = 500 Ω R2 = 500 Ω T _A = MIN t		=, 2, 2,	' ,	UNIT
			SN54A	LS648	SN74AL	S648A	
			MIN	MAX	MIN	MAX	
f _{max}			35		40		MHz
^t PLH	CLKBA or CLKAB	A or B	8	39	7	33	ns
^t PHL	CERBA OF CERAB	AOIB	5	23	5	20	115
^t PLH	A or B	B or A	3	20	2	17	ns
^t PHL		BUIA	2	12	2	10	115
^t PLH	SBA or SAB [‡]	A or B	5	44	5	39	ns
^t PHL	(stored data low)	A 01 B	4	26	4	22	113
^t PLH	SBA or SAB‡	A or B	6	30	6	25	ns
^t PHL	(stored data high)	AOID	6	25	6	21	113
^t PZH	OE	A or B	4	25	2	22	ns
^t PZL	UE	AOID	4	25	4	22	113
^t PHZ	DE	A or B	1	12	1	10	ns
^t PLZ	UE	7010	2	21	2	15	115
^t PZH	DIR	A or B	4	35	2	27	ns
^t PZL	DIK	AUID	3	25	3	19	115
^t PHZ	DIR	A or B	1	17	1	14	ns
^t PLZ	DIK	AOIB	2	22	2	15	113

[†] For conditions shown MIN or MAX, use the appropriate value specified under recommended operating conditions.

[‡] These parameters are measured with the internal output state of the storage register opposite that of the bus input.

SDAS039F - DECEMBER 1983 - REVISED JANUARY 1995

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V _{CC}		7 V
Input voltage, V _I : Control inputs		7 V
Operating free-air temperature range, T_{Δ} :	SN54AS646	-55°C to 125°C
,	SN74AS646	0°C to 70°C
Storage temperature range		-65°C to 150°C

recommended operating conditions

			SI	N54AS64	ŀ6	SN74AS646		UNIT	
			MIN	NOM	MAX	MIN	NOM	MAX	UNII
VCC	Supply voltage		4.5	5	5.5	4.5	5	5.5	V
V_{IH}	High-level input voltage		2			2			V
V_{IL}	Low-level input voltage				0.8			0.8	V
ЮН	High-level output current				-12			-15	mA
loL	Low-level output current				32			48	mA
fclock*	Clock frequency		0		75	0		90	MHz
+ *	Pulse duration	CLKBA or CLKAB high	6			5			
t _W *		CLKBA or CLKAB low	7			6			ns
t _{su} *	Setup time, A before CLKAB↑ or B before CLKBA↑		7			6			ns
th*	Hold time, A after CLKAB↑ or B before CLKBA		0		, and the second	0			ns
TA	Operating free-air temperature	·	-55		125	0		70	°C

^{*} On products compliant to MIL-STD-883, Class B, this parameter is based on characterization data but is not production tested.

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

SDAS039F - DECEMBER 1983 - REVISED JANUARY 1995

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS		SN	154AS64	16	SN	174AS64	6	LINUT
				MIN	TYP [†]	MAX	MIN	TYP [†]	MAX	UNIT
٧ıĸ		V _{CC} = 4.5 V,	I _I = -18 mA			-1.2			-1.2	V
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V},$	$I_{OH} = -2 \text{ mA}$	V _{CC} -2			V _{CC} -2			
\/~			$I_{OH} = -3 \text{ mA}$	2.4	3.2		2.4	3.2		V
VOН		$V_{CC} = 4.5 \text{ V}$	$I_{OH} = -12 \text{ mA}$	2						V
			$I_{OH} = -15 \text{ mA}$				2			
M		V _{CC} = 4.5 V	I _{OL} = 32 mA		0.25	0.5				V
VOL		VCC = 4.5 V	VCC = 4.5 V $IOL = 48 mA$					0.35	0.5	٧
ļ	Control inputs	$V_{CC} = 5.5 \text{ V},$	V _I = 7 V			0.1			0.1	mA
ΙĮ	A or B ports	$V_{CC} = 5.5 \text{ V},$	V _I = 5.5 V			0.1			0.1	
	Control inputs		V _I = 2:7 V			20			20	
IН	A or B ports‡	$V_{CC} = 5.5 \text{ V},$				70			70	μΑ
	Control input	V 55V	\ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \			-0.5			-0.5	
IIL	A or B ports ‡ VCC = 5.5 V,		V _I = 0.4 V			-0.75			-0.75	mA
ΙΟ§		V _{CC} = 5.5 V,	V _O = 2.25 V	-30		-112	-30		-112	mA
			Outputs high		120	195		120	195	
ICC		V _{CC} = 5.5 V	Outputs low		130	211		130	211	mA
			Outputs disabled		130	211		130	211	

 $[\]uparrow$ All typical values are at V_{CC} = 5 V, T_A = 25 °C.

[‡] For I/O ports, the parameters I_{IH} and I_{IL} include the off-state output current.

[§] The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, IOS.

SDAS039F - DECEMBER 1983 - REVISED JANUARY 1995

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V_{CC} = 4.5 V to 5.5 V, C_L = 50 pF, R1 = 500 Ω , R2 = 500 Ω , T_A = MIN to MAX †				UNIT
		l i	SN54A	\S646	SN74AS646		
			MIN	MAX	MIN	MAX	
f _{max} *			75		90		MHz
^t PLH	CLKBA or CLKAB	A or B	2	9.5	2	8.5	ns
^t PHL		AUID	2	10	2	9	115
^t PLH	A or B	B or A	2	11.5	2	9	ns
^t PHL		BUIA	1	8	1	7	115
^t PLH	SBA or SAB^‡	A or B	2	13.5	2	11	ns
^t PHL	SBA OF SAB +	AOIB	2	11	2	9	115
^t PZH	ŌĒ	A or B	2	11	2	9	ns
^t PZL	OE	AOIB	3	15	3	14	115
^t PHZ	ŌĒ	A or B	2	11	2	9	ns
^t PLZ	OE	AUID	2	11	2	9	115
^t PZH	DIR	A or B	3	21	3	16	ns
^t PZL		AUID	3	24	3	18	115
^t PHZ	DIP	A or B	2	12	2	10	20
^t PLZ	DIR	AUIB	2	12	2	10	ns

^{*} On products compliant to MIL-STD-883, Class B, this parameter is based on characterization data but is not production tested.

[†] For conditions shown MIN or MAX, use the appropriate value specified under recommended operating conditions.

[‡] These parameters are measured with the internal output state of the storage register opposite that of the bus input.

SDAS039F - DECEMBER 1983 - REVISED JANUARY 1995

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, V _{CC}		7 V
Input voltage, V _I : Control inputs		7 V
I/O ports		5.5 V
Operating free-air temperature range, T _A : SN74AS648	0°C to	70°C
Storage temperature range	-65°C to 1	150°C

recommended operating conditions

			SN74AS648			UNIT
			MIN	NOM	MAX	UNII
Vсс	V _{CC} Supply voltage			5	5.5	V
V_{IH}	High-level input voltage		2			V
V_{IL}	Low-level input voltage				0.8	V
ЮН	High-level output current				-15	mA
loL	Low-level output current				48	mA
fclock	Clock frequency		0		90	MHz
	Pulse duration	CLKBA or CLKAB high	5			20
t _W	ruise duration	CLKBA or CLKAB low	6			ns
t _{su}	Setup time, A before CLKAB↑ or B before CLKBA↑					ns
th	Hold time, A after CLKAB↑ or B before CLKBA		0			ns
TA	Operating free-air temperature				70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADAMETER		TEST CONDITIONS		SN	SN74AS648		
	PARAMETER	TEST CONDITIONS		MIN	TYP‡	MAX	UNIT
٧ıĸ		V _{CC} = 4.5 V,	I _I = -18 mA			-1.2	V
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V},$	$I_{OH} = -2 \text{ mA}$	V _{CC} -2			
۷он		V 45V	$I_{OH} = -3 \text{ mA}$	2.4	3.2		V
		V _{CC} = 4.5 V	$I_{OH} = -15 \text{ mA}$	2			
VOL		$V_{CC} = 4.5 V,$	$I_{OL} = 48 \text{ mA}$		0.35	0.5	V
ī.	Control inputs	V _{CC} = 5.5 V	V _I = 7 V			0.1	mA
l _l	A or B ports		V _I = 5.5 V			0.1	
	Control inputs	V _{CC} = 5.5 V,	V CONTO			20	
lιΗ	A or B ports§		V _I = 2.7' V			70 ^µ	μΑ
	Control input	V 55V	M. MANA			-0.5	
IIL	A or B ports§	$V_{CC} = 5.5 V$	V _I =0.4′ V			-0.75	mA
IO¶	•	V _{CC} = 5.5 V,	V _O = 2.25 V	-30		-112	mA
			Outputs high		110	185	
Icc		$V_{CC} = 5.5 V$	Outputs low		120	195	mA
			Outputs disabled		120	195	

[‡] All typical values are at V_{CC} = 5 V, T_A = 25 °C.

The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, los.



[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

[§] For I/O ports, the parameters I_{IH} and I_{IL} include the off-state output current.

SDAS039F - DECEMBER 1983 - REVISED JANUARY 1995

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V_{CC} = 4.5 V to 5.5 V, C_L = 50 pF, $R1$ = 500 Ω , $R2$ = 500 Ω , T_A = MIN to MAX [†]		UNIT
			SN74/		
			MIN	MAX	
f _{max}			90	-	MHz
^t PLH	CLKBA or CLKAB A or B	A or B	2	8.5	ns
^t PHL		A 01 B	2	9	113
^t PLH	A or B	B or A	2	8	ns
^t PHL		B 01 A	1	7	113
^t PLH	SBA or SAB^‡	A or B	2	11	ns
^t PHL	SBA UI SAB +	A 01 B	2	9	113
^t PZH	O E	A or B	2	9	ns
^t PZL	OE .	A 01 B	3	15	113
^t PHZ	ŌĒ	A or B	2	9	ns
^t PLZ	J OE	A 01 B	2	9	113
^t PZH	DIR	A or B	3	16	ns
^t PZL	JIIV	A 01 D	3	18	115
^t PHZ	DIR	A or B	2	10	ne
^t PLZ	BIK	A 01 B	2	10	ns

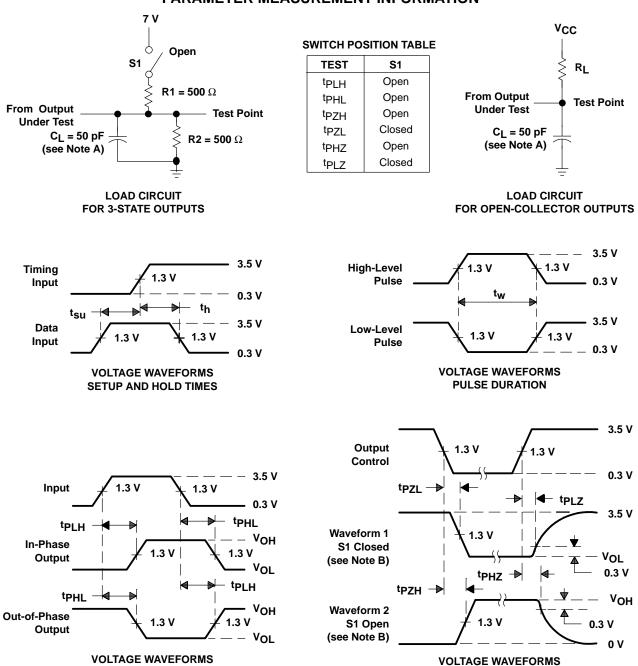
[†] For conditions shown MIN or MAX, use the appropriate value specified under recommended operating conditions.

[‡] These parameters are measured with the internal output state of the storage register opposite that of the bus input.

SDAS039F - DECEMBER 1983 - REVISED JANUARY 1995

ENABLE AND DISABLE TIMES, 3-STATE OUTPUTS

PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and jig capacitance.

PROPAGATION DELAY TIMES

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, $Z_Q = 50 \Omega$, $t_f \leq$ 2 ns, $t_f \leq$ 2 ns.
- D. The outputs are measured one at a time with one transition per measurement.

Figure 2. Load Circuits and Voltage Waveforms



IMPORTANT NOTICE

Texas Instruments (TI) reserves the right to make changes to its products or to discontinue any semiconductor product or service without notice, and advises its customers to obtain the latest version of relevant information to verify, before placing orders, that the information being relied on is current.

TI warrants performance of its semiconductor products and related software to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

Certain applications using semiconductor products may involve potential risks of death, personal injury, or severe property or environmental damage ("Critical Applications").

TI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, INTENDED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT APPLICATIONS, DEVICES OR SYSTEMS OR OTHER CRITICAL APPLICATIONS.

Inclusion of TI products in such applications is understood to be fully at the risk of the customer. Use of TI products in such applications requires the written approval of an appropriate TI officer. Questions concerning potential risk applications should be directed to TI through a local SC sales office.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards should be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance, customer product design, software performance, or infringement of patents or services described herein. Nor does TI warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used.

Copyright © 1996, Texas Instruments Incorporated